



SCCS014 - May 1994 - Revised February 2000

## CY54/74FCT157T

# Quad 2-Input Multiplexer

## Features

- Function, pinout, and drive compatible with FCT and F logic
- FCT-C speed at 4.3 ns max. (Com'l), FCT-A speed at 5.0 ns max. (Com'l)
- Reduced  $V_{OH}$  (typically = 3.3V) versions of equivalent FCT functions
- Edge-rate control circuitry for significantly improved noise characteristics
- Power-off disable feature
- Matched rise and fall times
- Fully compatible with TTL input and output logic levels
- ESD > 2000V
- Extended commercial range of  $-40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$
- Sink current 64 mA (Com'l), 32 mA (Mil)
- Source current 32 mA (Com'l), 12 mA (Mil)

## Functional Description

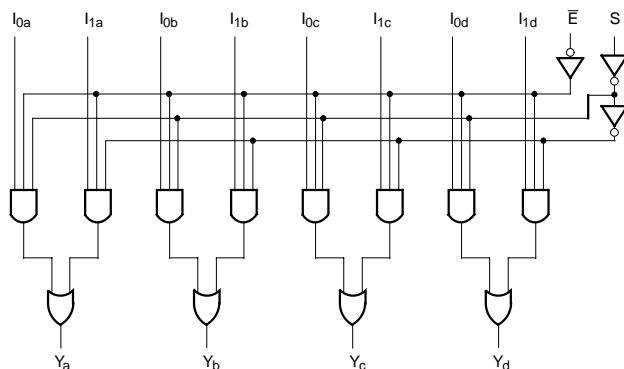
The FCT157T is a quad two-input multiplexer that selects four bits of data from two sources under the control of a common data Select input (S). The Enable input (E) is Active LOW. When ( $\bar{E}$ ) is HIGH, all of the outputs (Y) are forced LOW regardless of all other input conditions.

Moving data from two groups of registers to four common output buses is a common use of the FCT157T. The state of the Select input determines the particular register from which the data comes. It can also be used as a function generator. The device is useful for implementing highly irregular logic by generating any four of the sixteen different functions of two variables with one variable common.

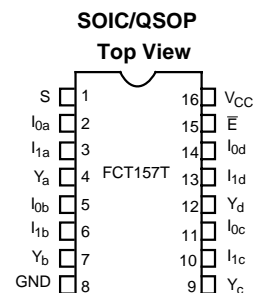
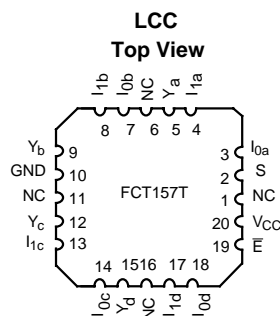
The FCT157T is a logic implementation of a four-pole, two-position switch where the position of the switch is determined by the logic levels supplied to the Select input.

The outputs are designed with a power-off disable feature to allow for live insertion of boards.

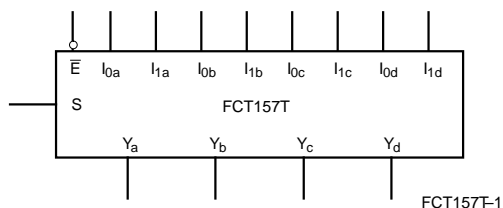
## Logic Block Diagram, FCT157T



## Pin Configurations



## Logic Symbol



**Pin Description**

Name	Description
S	Common Select Input
$\bar{E}$	Enable Inputs (Active LOW)
I <sub>0</sub>	Data Inputs from Source 0
I <sub>1</sub>	Data Inputs from Source 1
Y	Non-Inverted Output

**Function Table<sup>[1]</sup>**

Inputs				Outputs
E	S	I <sub>0</sub>	I <sub>1</sub>	Y
H	X	X	X	L
L	H	X	L	L
L	H	X	H	H
L	L	L	X	L
L	L	H	X	H

**Maximum Ratings<sup>[2,3]</sup>**

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... -65°C to +150°C

Ambient Temperature with

Power Applied ..... -65°C to +135°C

Supply Voltage to Ground Potential..... -0.5V to +7.0V

DC Input Voltage ..... -0.5V to +7.0V

DC Output Voltage ..... -0.5V to +7.0V

DC Output Current (Maximum Sink Current/Pin) ..... 120 mA

Power Dissipation ..... 0.5W

Static Discharge Voltage..... >2001V  
(per MIL-STD-883, Method 3015)

**Operating Range**

Range	Range	Ambient Temperature	V <sub>CC</sub>
Commercial	All	-40°C to +85°C	5V ± 5%
Military <sup>[4]</sup>	All	-55°C to +125°C	5V ± 10%

**Electrical Characteristics** Over the Operating Range

Parameter	Description	Test Conditions		Min.	Typ. <sup>[5]</sup>	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> =Min., I <sub>OH</sub> =-32 mA	Com'l	2.0			V
		V <sub>CC</sub> =Min., I <sub>OH</sub> =-15 mA	Com'l	2.4	3.3		V
		V <sub>CC</sub> =Min., I <sub>OH</sub> =-12 mA	Mil	2.4	3.3		V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> =Min., I <sub>OL</sub> =64 mA	Com'l		0.3	0.55	V
		V <sub>CC</sub> =Min., I <sub>OL</sub> =32 mA	Mil		0.3	0.55	V
V <sub>IH</sub>	Input HIGH Voltage			2.0			V
V <sub>IL</sub>	Input LOW Voltage					0.8	V
V <sub>H</sub>	Hysteresis <sup>[6]</sup>	All inputs			0.2		V
V <sub>IK</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> =Min., I <sub>IN</sub> =-18 mA			-0.7	-1.2	V
I <sub>I</sub>	Input HIGH Current	V <sub>CC</sub> =Max., V <sub>IN</sub> =V <sub>CC</sub>				5	μA
I <sub>IH</sub>	Input HIGH Current	V <sub>CC</sub> =Max., V <sub>IN</sub> =2.7V				±1	μA
I <sub>IL</sub>	Input LOW Current	V <sub>CC</sub> =Max., V <sub>IN</sub> =0.5V				±1	μA
I <sub>OZH</sub>	Off State HIGH-Level Output Current	V <sub>CC</sub> = Max., V <sub>OUT</sub> = 2.7V				10	μA
I <sub>OZL</sub>	Off State LOW-Level Output Current	V <sub>CC</sub> = Max., V <sub>OUT</sub> = 0.5V				-10	μA
I <sub>OS</sub>	Output Short Circuit Current <sup>[7]</sup>	V <sub>CC</sub> =Max., V <sub>OUT</sub> =0.0V		-60	-120	-225	mA
I <sub>OFF</sub>	Power-Off Disable	V <sub>CC</sub> =0V, V <sub>OUT</sub> =4.5V				±1	μA

**Note:**

1. H = HIGH Voltage Level. L = LOW Voltage Level. X = Don't Care
2. Unless otherwise noted, these limits are over the operating free-air temperature range.
3. Unused inputs must always be connected to an appropriate logic voltage level, preferably either V<sub>CC</sub> or ground.
4. T<sub>A</sub> is the "instant on" case temperature.
5. Typical values are at V<sub>CC</sub>=5.0V, T<sub>A</sub>=+25°C ambient.
6. This parameter is specified but not tested.
7. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parametric tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.

**Capacitance<sup>[6]</sup>**

Parameter	Description	Typ. <sup>[5]</sup>	Max.	Unit
$C_{IN}$	Input Capacitance	5	10	pF
$C_{OUT}$	Output Capacitance	9	12	pF

**Power Supply Characteristics**

Parameter	Description	Test Conditions	Typ. <sup>[5]</sup>	Max.	Unit
$I_{CC}$	Quiescent Power Supply Current	$V_{CC}=\text{Max.}, V_{IN}\leq 0.2V, V_{IN}\geq V_{CC}-0.2V$	0.1	0.2	mA
$\Delta I_{CC}$	Quiescent Power Supply Current (TTL inputs HIGH)	$V_{CC}=\text{Max.}, V_{IN}=3.4V^{[8]}$ $f_1=0$ , Outputs Open	0.5	2.0	mA
$I_{CCD}$	Dynamic Power Supply Current <sup>[9]</sup>	$V_{CC}=\text{Max.}$ , One Input Toggling, 50% Duty Cycle, Outputs Open, $\overline{OE}=\text{GND}, V_{IN}\leq 0.2V$ or $V_{IN}\geq V_{CC}-0.2V$	0.06	0.12	mA/MHz
$I_C$	Total Power Supply Current <sup>[10]</sup>	$V_{CC}=\text{Max.}$ , 50% Duty Cycle, Outputs Open, One Input Toggling at $f_1=10\text{ MHz}$ , $\overline{OE}=\text{GND}, V_{IN}\leq 0.2V$ or $V_{IN}\geq V_{CC}-0.2V$	0.7	1.4	mA
		$V_{CC}=\text{Max.}$ , 50% Duty Cycle, Outputs Open, One Input Toggling at $f_1=10\text{ MHz}$ , $\overline{OE}=\text{GND}, V_{IN}=3.4V$ or $V_{IN}=\text{GND}$	1.0	2.4	mA
		$V_{CC}=\text{Max.}$ , 50% Duty Cycle, Outputs Open, Four Bits Toggling at $f_1=2.5\text{ MHz}$ , $\overline{OE}=\text{GND}, V_{IN}\leq 0.2V$ or $V_{IN}\geq V_{CC}-0.2V$	0.7	1.4 <sup>[11]</sup>	mA
		$V_{CC}=\text{Max.}$ , 50% Duty Cycle, Outputs Open, Four Bits Toggling at $f_1=2.5\text{ MHz}$ , $\overline{OE}=\text{GND}, V_{IN}=3.4V$ or $V_{IN}=\text{GND}$	1.7	5.4 <sup>[11]</sup>	mA

**Notes:**

8. Per TTL driven input ( $V_{IN}=3.4V$ ); all other inputs at  $V_{CC}$  or GND.
9. This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
10.  $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$   
 $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD}(f_0/2 + f_1 N_1)$   
 $I_{CC}$  = Quiescent Current with CMOS input levels  
 $\Delta I_{CC}$  = Power Supply Current for a TTL HIGH input ( $V_{IN}=3.4V$ )  
 $D_H$  = Duty Cycle for TTL inputs HIGH  
 $N_T$  = Number of TTL inputs at  $D_H$   
 $I_{CCD}$  = Dynamic Current caused by an input transition pair (HLH or LHL)  
 $f_0$  = Clock frequency for registered devices, otherwise zero  
 $f_1$  = Input signal frequency  
 $N_1$  = Number of inputs changing at  $f_1$   
 All currents are in milliamps and all frequencies are in megahertz.
11. Values for these conditions are examples of the  $I_{CC}$  formula. These limits are specified but not tested.

**Switching Characteristics** Over the Operating Range

Parameter	Description	FCT157T		FCT157AT				FCT157CT		Unit	Fig. No. <sup>[13]</sup>
		Commercial		Military		Commercial		Commercial			
		Min. <sup>[12]</sup>	Max.	Min. <sup>[12]</sup>	Max.	Min. <sup>[12]</sup>	Max.	Min. <sup>[12]</sup>	Max.		
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay I to Y	1.5	6.0	1.5	5.8	1.5	5.0	1.5	4.3	ns	1, 3
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay E to Y	1.5	10.5	1.5	7.4	1.5	6.0	1.5	4.8	ns	1, 5
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay S to Y	1.5	10.5	1.5	8.1	1.5	7.0	1.5	5.2	ns	1, 3

**Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
4.3	CY74FCT157CTQCT	Q1	16-Lead (150-Mil) QSOP	Commercial
	CY74FCT157CTSOC/SOCT	S1	16-Lead (300-Mil) Molded SOIC	
5.0	CY74FCT157ATQCT	Q1	16-Lead (150-Mil) QSOP	Commercial
	CY74FCT157ATSOC/SOCT	S1	16-Lead (300-Mil) Molded SOIC	
5.8	CY54FCT157ATLMB	L61	20-Pin Square Leadless Chip Carrier	Military

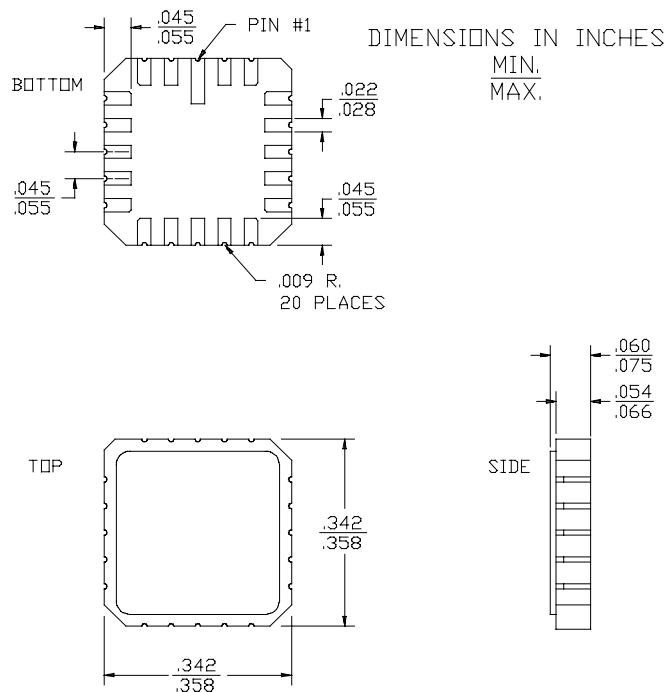
**Note:**

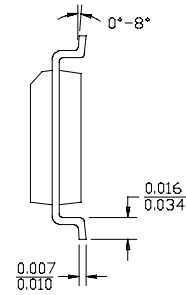
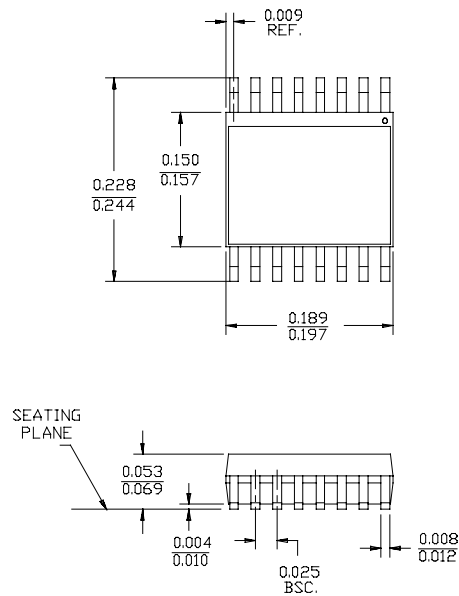
12. Minimum limits are specified but not tested on Propagation Delays.  
 13. See "Parameter Measurement Information" in the General Information Section

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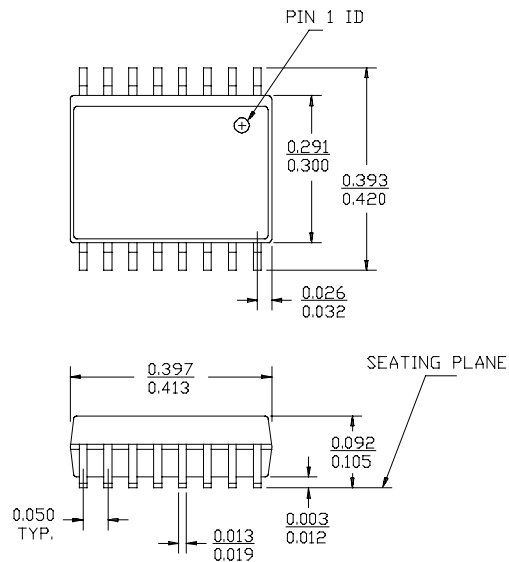
**Package Diagrams**
**20-Pin Square Leadless Chip Carrier L61**

MIL-STD-1835 C-2A

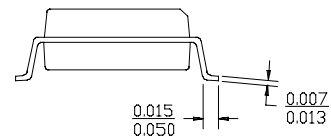


**Package Diagrams (continued)**
**16-Lead Quarter Size Outline Q1**


DIMENSIONS IN INCHES MIN.  
MAX.  
LEAD COPLANARITY 0.004 MAX.

**16-Lead Molded SOIC S1**


DIMENSIONS IN INCHES MIN.  
MAX.  
LEAD COPLANARITY 0.004 MAX.



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